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Applicants: Takuji HIMENO et al.

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For: **IMAGE DATA PROCESSING APPARATUS AND METHOD**

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Search Report of International Application No. PCT/JP03/08433. Also enclosed is a copy of Form PTO-1449 and the International Search Report.

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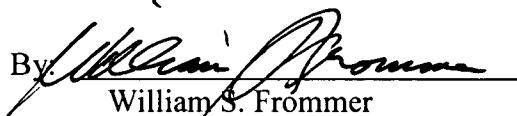
REMARKS

Entry of this Information Disclosure Statement and an early examination on the merits are respectfully solicited.

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Respectfully submitted,

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Enclosures

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	AM	JP 2000-92448	03/31/00	Japan			
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